Application/Control No. O9/507,212 Applicant(s)/Patent Under Reexamination YAMASHITA, SEIJI Examiner Thao T. Tran Applicant(s)/Patent Under Reexamination YAMASHITA, SEIJI Page 1 of 1

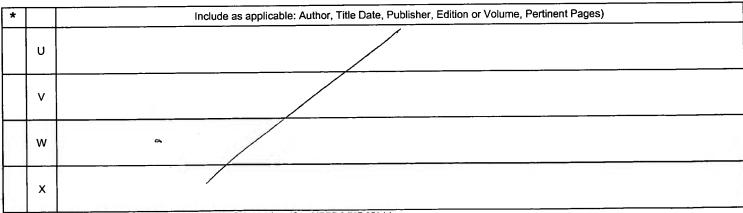
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	Α	US-5,562,820	10-1996	Taoda et al.	210/94
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	М	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS



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